


<b>Search Notes</b>  	<b>Application/Control No.</b>  10540997	<b>Applicant(s)/Patent Under Reexamination</b>  LEE, CHEOL-SU
	<b>Examiner</b>  DEBRA ANTONIENKO	<b>Art Unit</b>  3689

SEARCHED			
Class	Subclass	Date	Examiner
705	1	08/17/2008	DA

SEARCH NOTES		
Search Notes	Date	Examiner
East - see search notes	08/17/2008	DA
East - see search notes	12/9/2009	DA
Google - see search notes	12/9/2009	DA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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